

Notice of References Cited	Application/Control No. 10/707,518	Applicant(s)/Patent Under Reexamination CHEN ET AL.
	Examiner Matthew G. Kayrish	Art Unit 2653

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0142610	07-2003	Yeh et al.	369/75.2
*	B	US-5,828,537	10-1998	d'Alayer de Costemore d'Arc, Stephane M. A.	360/137
*	C	US-2004/0117807	06-2004	Takahashi et al.	720/610
*	D	US-4,425,016	01-1984	Denckert, Lennart H.	439/304
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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